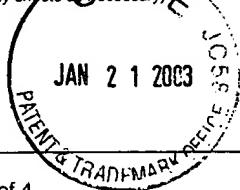


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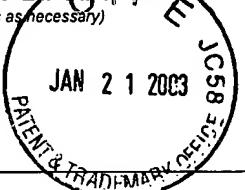
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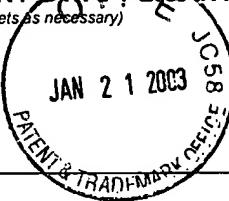
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		Group Art Unit	1745
		Examiner Name	Unknown
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		Group Art Unit	1745
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